



TS IEC 62804-1:2015

Photovoltaic (PV) Modules - Test Methods for the detection of potential-induced degradation (PID)

Part 1: Crystalline silicone
Confirmation of test results

VDE Renewables File Ref.: 10116/2017-40281

Applicant: Sharp Electronics GmbH
Nagelsweg 33-35
20097 Hamburg

Product: Crystalline silicon Photovoltaic (PV)-Modules

Type: NU-RCXXX
NU-RDXXX
ND-RCXXX,

XXX in the type replaces the power in watt and can be any number between:
295 – 315 W

Manufacturer: Sharp Electronics GmbH

Standard: TS IEC 62804-1:2015

Test conditions

Testing time: 96 h
Chamber temperature: 60 °C
Relative Humidity: 85 %
Potential to ground: - 1000 V

Pass criteria

Power degradation: < 5%
Dry Insulation: > 40 MΩm²
Wet insulation: > 40 MΩm²



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Summary of test results:

Maximum power degradation:	allowed	max. 5 %
	measured	max. 0.8 %

The measured degradation is below the allowed degradation.

Dry insulation resistance:	required	min. 24 MΩ
	measured	> 500 MΩ

The measured dry insulation resistance is above the limit.

Wet insulation resistance:	required	min. 24 MΩ
	measured	> 500 MΩ

The measured wet insulation resistance is above the limit.

Visual inspection: No findings

The complete test results and the relevant bill of materials are given in Test Report No.: TRPVM-2017-40281-1.

VDE Renewables GmbH

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